

**Notice of References Cited**

Application/Control No.

10/520,901

Applicant(s)/Patent Under

Reexamination

FUJIWARA ET AL.

Examiner

WU-CHENG Winston SHEN

Art Unit

1632

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
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H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	PCT/US01/27127 (page1-2)	03-2002	WO 02/20754	Stuart et al.	C12N 15/00
O	PCT/EP00/00265 (page 1)	07-2000	WO 00/42208	Nemerow et al.	C12N 15/85
P	PCT/US00/00390 (page 1)	07-2000	WO 00/40741	Arya et al.	C12N 15/867
Q	PCT/EP98/08216 (page 1)	07-1999	WO 99/33998	Hagen et al.	C12N 15/54
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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